

Application/Control	No
10/551 719	

Examiner Tam Nguyen Applicant(s)/Patent under Reexamination CHAE, HEE-SEON

Art Unit 3764

			ISSUE	CL	.AS	SIF	<u>ICAT</u>	ION						
	OR	GINAL		INTERNATIONAL CLASSIFICATION										
	CLASS	CLASS CLAIMED						AIMED						
	482	1	Α	63	В	22	/00		1					
	CROSS R	EFERENCES		Α	63	В	22	/14		1				
CLASS	SUBCLASS	ONE SUBCLASS PE	R BLOCK)											
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am (Assi	JERO PRIM	ARY E	ONNE	LLLY NER	Total Claims Allowed: 4									
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(Legai In	struments Exan							2						

⊠c	Claims renumbered in the same order as presented by applicant								☐ CPA			☐ T.D.			☐ R.1.47				
Final	Original		Final	Original		Final	Original		Final	Original		Final	Original		Final	Original		Final	Original
1	1			31	1		61			91			121			151			181
	2			32			62			92			122			152			182
2	3			33			63			93			123			153			183
3	4			34			64			94			124			154			184
4	5			35			65			95			125			155			185
	6			36	]		66			96			126			156			186
	7			37	]		67			97			127			157			187
	8			38	}	_	68			98			128			158			188
	9			39			69			99			129			159			189
	10			40	1		70			100			130			160			190
	11			41	]		71			101			131			161			191
	12			42	1		72			102			132			162			192
	13			43			73			103		-	133			163			193
	14			44	1		74			104			134			164			194
	15			45	1		75			105			135			165			195
	16			46	1		76			106			136			166			196
	17			47	1		77			107			137			167			197
	18			48	1		78			108			138			168			198
	19			49	1		79			109			139			169			199
	20	1		50	1		80			110			140			170			200
	21	Ì		51	1		81			111			141			171			201
	22			52			82			112			142			172			202
	23			53			83			113			143			173			203
	24	1		54	1		84			114			144			174			204
	25			55			85			115			145			175			205
	26	]		56	]		86			116			146			176			206
	27			57			87			117			147			177			207
	28	]		58			88			118			148			178			208
	29	]		59			89			119			149			179			209
	30	<u> </u>		60			90			120			150			180			210